

<b>Notice of References Cited</b>	Application/Control No. 09/353,777	Applicant(s)/Patent Under Reexamination KAGAWA ET AL.	
	Examiner Mike Qi	Art Unit 2871	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,229,586	05-2001	Date et al	349/113
	B	US-6,219,120	04-2001	Sasaki et al	349/113
	C	US-6,414,734	07-2002	Shigeta et al	349/113
	D	US-4,456,336	06-1984	Chung et al	350/338
	E	US-3,787,110	01-1974	Berremman et al	350/160
	F	US-5,965,691	10-1999	Gibbons et al	528/353
	G	US-6,373,538	04-2002	Okumura et al	349/106
	H	US-6,437,844	08-2002	hattori et al	349/129
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Southward et al, "Control of Reflectivity and Surface Conductivity in Metallized Polyimide Films Prepared via in Situ Silver (I) Reduction" Chem. Mater. 1997,9, 501-510.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.